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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO	
10/600,235	06/19/2003	Gary K. Richmond	7281-US 9810		
7590 01/28/2004			EXAMINER ·		
Thomas F. Le		DESTA, ELIAS			
TEKTRONIX, M/S 50-LAW	INC.	ART UNIT	PAPER NUMBER		
P.O. Box 500		2857			
Beaverton, OR	97077-0001	DATE MAN ED ONOMOOA			

DATE MAILED: 01/28/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

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		Applicati	on No.	Applicant(s)	(Co				
Office Action Summan		10/600,2	35	RICHMOND, GARY K.					
	Office Action Summary	Examine	r	Art Unit					
		Elias Des		2857					
	The MAILING DATE of this communication a or Reply	appears on the	e cover sheet with the	correspondence add	dress				
THE - Exte after - If the - If NO - Failu - Any	ORTENED STATUTORY PERIOD FOR REF MAILING DATE OF THIS COMMUNICATION insions of time may be available under the provisions of 37 CFR SIX (6) MONTHS from the mailing date of this communication. It is period for reply specified above is less than thirty (30) days, a proper of the provision of the	N. 1.136(a). In no ev reply within the star od will apply and w tute, cause the app	ent, however, may a reply be to tutory minimum of thirty (30) da rill expire SIX (6) MONTHS fror plication to become ABANDON	imely filed ays will be considered timely in the mailing date of this co ED (35 U.S.C. § 133).	mmunication.				
1)⊠	Responsive to communication(s) filed on 06	<u>8/13/2003</u> .							
2a) <u></u> ☐	This action is FINAL : 2b)⊠ Th	nis action is n	on-final.						
3)□	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.								
Disposit	ion of Claims								
4)⊠	4)⊠ Claim(s) <u>1-21</u> is/are pending in the application. 4a) Of the above claim(s) is/are withdrawn from consideration.								
5)□	Claim(s) is/are allowed.								
	⊠ Claim(s) <u>1-10 and 12-17</u> is/are rejected.								
7)🖾	☐ Claim(s) 11 and 18-21 is/are objected to.								
8)□	Claim(s) are subject to restriction and	d/or election r	equirement.						
Applicat	ion Papers								
9)⊠ The specification is objected to by the Examiner.									
10)	10) ☐ The drawing(s) filed on is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.								
	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a). Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).								
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	The oath or declaration is objected to by the	Examiner. N	ote the attached Onic	e Action of form FT	0-152.				
_	under 35 U.S.C. §§ 119 and 120			(-) (-l) (f)					
* \$ 13)	Acknowledgment is made of a claim for fore All b) Some * c) None of: 1. Certified copies of the priority docume 2. Certified copies of the priority docume 3. Copies of the certified copies of the p application from the International Burd See the attached detailed Office action for a lacknowledgment is made of a claim for domestince a specific reference was included in the B7 CFR 1.78. a) The translation of the foreign language Acknowledgment is made of a claim for domestince was included in the first sentence of	ents have beents have beents have been irority documeau (PCT Rulist of the certestic priority unfirst sentence provisional apestic priority unestic priority unestication in the priority	en received. en received in Applica ents have been receiv le 17.2(a)). ified copies not receiv nder 35 U.S.C. § 119 e of the specification of oplication has been re- ander 35 U.S.C. §§ 12	tion No yed in this National street. (e) (to a provisional or in an Application leceived. 0 and/or 121 since a	application) Data Sheet. a specific				
Attachmer	nt(s)								
2) Notice	ce of References Cited (PTO-892) ce of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449) Paper No(s	s) <u>06/13/2003</u> .	4) Interview Summar 5) Notice of Informal 6) Other:						

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Detailed Action

Abstract

1. Applicant is reminded of the proper content of an abstract of the disclosure; in the instant application, the abstract is too short in explaining the technical disclosure of the improvement.

Claim Objection

- 2. Claim 3 is objected to because of the following minor informalities:
 - ➤ Page 19, line 16, insert "are" after transitions.

Claim rejection - 35 U.S.C. 102

3. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) The invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 4. <u>Claims 1-10 and 12-17</u> are rejected under 35 U.S.C. 102(b) as anticipated by <u>Hall, Jr</u>. (U.S. Patent 4,349,896).

In reference to claims 1 and 10: Hall, Jr. teaches an apparatus that includes:

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An analog sampling array (see <u>Hall, Jr</u>., Fig. 2, signals from receivers 24's), for acquiring from the signal under test (SUT) (or acoustic signals from the wheels) a plurality of temporally offset analog samples during each of the sequence of sample periods (see signals from the receiver in Fig. 2 and Fig. 3, from the output);

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➤ A plurality of sample processors (see <u>Hall, Jr</u>., Figs. 4-5), for identifying logic level transactions between respective current and previous samples and for determining a time of occurrence of the logic level transaction (see <u>Hall, Jr</u>., column 4, lines 44-63); and

Further, Hall, Ir. also includes a method for

- ➤ Determining a logic level for each of the analog samples using a threshold signal level (see *Hall, Jr*., Figs. 2 and 3);
- ➤ Generate edge bin data structure (see <u>Hall, Jr</u>., Fig. 5, output from member 42 or the peak detector); and
- ➤ Edge bin data structure includes identification of a sample associated with logic level transition and estimation of the relative threshold level crossing time of the signal under test (SUT) between successive sample (see *Hall, Jr.*, Fig. 2, transmitter burst with suppressed noise in between successive signals, such as shear wave).

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With regard to claim 2: as noted above in claim 1, <u>Hall, Jr</u>. further teaches that the apparatus includes a time stamp processor, for imparting a time stamp to sample data indicative of respective sample times (see <u>Hall, Jr</u>., column 5, line 64 to column 6, line 8).

With regard to claim 3: as noted above in claim 1, <u>Hall, Jr</u>. further teaches that the samples are acquired and logic level transitions are identified in real time (see *Hall, Jr.*, column 4, lines 44-51).

With regard to claim 4: as noted above in claim 1, <u>Hall, Jr</u>. further teaches that the sample intervals are defined as respective temporal portions of a period of a clock (see <u>Hall, Jr</u>., column 4, line 64 to column 5, line 26).

With regard to claim 5: as noted above in claim 1, Hall, Ir. further teaches that the plurality of processors shown in Fig. 5 include a convolution and pick detector, hence it is inherent for each sample period, each the sample processor receives respective current sample (Vc) and respective previous sample (Vp) and responsively produces sample data including indication of logic level of the current sample (L), such as identifying logic level transition between the current and previous samples (E) and estimated time of occurrence of the identified logic level transition.

With regard to claims 6 and 11: as noted above in claim 5, <u>Hall, Jr</u>. further teaches that the apparatus includes reduction logic (see <u>Hall, Jr</u>., Fig. 2, removing inherent system noise using thresholds and amplitude detection), for reducing the

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amount data provided to the time stamp processor by discarding (removing the noise component, see *Hall, Ir.*, column 4, lines 19-37) sample data not associated with an identified logic level transition.

<u>With regard to claim 7</u>: as noted in claim 6, <u>Hall, Jr</u>. further teaches that the sample data produced by each sample processors (see Fig. 5, Expanded output) is associated with a respective slice identifier (see <u>Hall, Jr</u>., Fig. 5, peak detector).

With regard to claim 9: as noted above in claim 1, <u>Hall, Ir</u>. further teaches that the sample data where the system includes a plurality of instances of the apparatus are used to process respective signals under test including a clock signal and a data signal (see <u>Hall, Ir</u>., Fig. 5, member 44, signal from pick detector and clock signal to 44).

With regard to claim 12: as noted above in claim 10, <u>Hall, Jr</u>. further teaches that the signal under test (SUT) includes a data signal, and the edge bin data (see Fig. 5, data from pick detector) structure, which includes logic level indicator [see <u>Hall, Jr.</u>, Fig. 5, the output from "compression wave storage" or member 44, since all the input member 30 (sample & hold) or member 44 provide a logic level indicator for the purposes of conversion form analog to digital signal].

With regard to claim 13: as noted above in claim 10, <u>Hall, Jr</u>. further teaches that the edge bin structure (pick detector) includes a time stamp indicative of the time of a respective threshold level transition of the signal under test (SUT) (input

signal from the receiver as shown in Figs. 4 and 5; output that is delayed or time expanded output).

With regard to claims 14 and 17: as noted above in claim 10, <u>Hall, Jr</u>. further teaches that the method is used to process each of a plurality of signals under test including clock signal and a data signal to produce corresponding list of edge bins (edge detected signals (see *Hall, Jr.*, Fig. 5, output from member 42); and processing each data signal edge list with the clock signal edge bin list (since clock signals are triggered at some transition time) to identify, for each clock signal edge, corresponding logic value of the data signal (the expanded output from member 44 of Fig. 5).

With regard to claims 15 and 16: as noted above in claim 14, <u>Hall, Jr</u>. further teaches that the method of processing each data signal edge bin list (pick detected) with the clock signal edge bin (clock) list to identify a timing violation because in sampling and holding, it is inherent that a rule has to have a way to detecting a violation since convolution operation or an A/D conversion would not have been possible under the circumstances (as shown in Fig. 5).

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Allowable Subject Matter

5. <u>Claims 11 and 18-21</u> are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Conclusion

- 6. The prior art made of record and not relied upon is considered pertinent to applicant disclosure:
 - ➤ <u>Doggett</u> (U.S. Patent 4,598,398) teaches test apparatus for PCM/FDM trans-multiplexer.
 - ➤ <u>Gribbes et al.</u> (U.S. Patent 4,204,433) teaches computerized ultrasonic scanner with technique select.
 - Bauernfeind et al. (U.S. Patent 4,302,843) teaches method and apparatus for measuring transmission characteristics of test object during communication gap.
 - > <u>Payton et al.</u> (U.S. Patent 4,168,485) teaches simultaneous use of pseudo-random control signals in vibration exploration method.
 - Meditch et al. (IRE Publication, 'On the Real-Time Control of Time-Varying Linear System') teaches a new class of sampled data controls for time varying dynamic process.

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<u>Lewes</u> (IEEE Article, 'Optimizing the Stage Resolution in Pipelined,
 Multistage, Analog-to-Digital Converters for Video-Rate Applications')
 teaches the effect of stage resolution on the characteristics of
 monolithic, pipelined, multi-state, analog-to-digital converters (ADCs).

7. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Elias Desta whose telephone number is (703)-305-3840. The examiner can normally be reached on M-Thu (8:00-6:30).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Marc S. Hoff can be reached on (703)-308-1677. The fax phone numbers for the organization where this application or proceeding is assigned are (703)-308-5841 for regular communications and (703)-308-5841 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703)-308-1782.

Elias Desta Examiner Art Unit 2857

-ed

January 15, 2004

MARC S. HOFF SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800

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